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APPLICANT

Marvin LIAO, et al.

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GROUP ART UNIT

2814

LIST OF REFERENCES CITED BY APPLICANT
(Use Several Sheets if Necessary)

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TL	AA	4,173,661	11/1979	Bourdon			
	AB	4,420,498	12/1983	Hirose, et al.			
	AC	4,486,462	12/1984	Asahi, et al.			
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TL	AP	EP0397131 A2	11/1990	Europe	X
	AQ	EP0711846 A1	5/1996	Europe	X
	AR	JP63-229814	9/1988	Japan	X**
	AS	JP3-135018	6/1991	Japan	X**
	AT	JP4-100221	4/1992	Japan	X**
TL	AU	JP6-120152	4/1994	Japan	X**

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TL	AV	Wang, C.K., et al., "Optimization of PVD Ti/CVD TiN Liner for 0.35 µm Tungsten Plug Technology", Mat. Res. Society Symp. Proc., Vol. 427, p. 383-387 (1996).	DATE CONSIDERED 10/20/03
EXAMINER	T. Rucan		

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

**English Abstract Provided